
Claim 32 (New)

The method recited in Claim 1 wherein said light source is adjusted in configuration by a lateral movement.

Claim 33 (New)

B1 The method recited in Claim 1 wherein said light source is adjusted in configuration by a rotational movement.

Claim 34 (New)

The apparatus recited in Claim 12 wherein said light source is operatively arranged to be adjusted in configuration by a lateral movement.

Claim 35 (New)

The apparatus recited in Claim 12 wherein said light source is operatively arranged to be adjusted in configuration by a rotational movement.

Please amend Claims 1, 12, 15, 23, and 27-31 as follows:

Claim 1 (Twice Amended)

B2
A method for aligning the optical beam path of a microscope, having a light source (1), a microscope optical system, a detection stop (12), and a detection device (13), wherein the method comprises the steps of:

- a) providing a center of the detection stop (12) as a first optical reference point;
- b) providing a second optical reference point wherein an entire beam path is defined by said first optical reference point and said second optical reference point; and,
- c) carrying out an iterative alignment by adjusting the configuration of the light source until the entire beam path is between said first optical reference point and said second optical reference point.

Claim 12 (Amended)

B3
A microscope assemblage, having a light source (1), a microscope optical system, a detection device (13), a detection stop (12) defining a first optical reference point and a second optical reference point wherein an entire beam path is defined by said first optical reference point and said second optical reference point, and said light source is operatively arranged to be adjusted in configuration.

Claim 15 (Amended)

B4
The microscope assemblage as defined in Claim 14, characterized in that the focus of the resonator light bundle of the laser resonator in the laser resonator serves as an intra-laser point light source (19).

Claim 23 (Amended)

B5 The microscope assemblage as defined in Claim 22, characterized in that the lateral displacement of the point light source is accomplished by way of a lateral displacement of an illumination stop (3).

Claim 27 (Twice Amended)

B6 The microscope assemblage as defined in Claim 13, characterized in that the illuminating light beam is rotated or tilted about an illumination stop (3).

Claim 28 (Amended)

B7 A method for aligning the optical beam path of a microscope, having a light source (1), a microscope optical system, a detection stop (12), and a detection device (13), wherein the method comprises the steps of:

- a) providing the plane of the detection stop (12) as a first optical reference plane;
- b) providing a second reference plane wherein an entire beam path is defined as perpendicular to said first optical reference plane and said second optical reference plane and through a center of said detection stop; and,
- c) carrying out an iterative alignment by adjusting the configuration of the light source until the entire beam path is perpendicular to said first optical reference plane and said second optical reference plane and through a center of said detection stop.

Claim 29 (Amended)

The method as defined in Claim 28, characterized in that all optical elements are aligned with respect to the reference planes.